ABSTRACT

Burn-in station for performing burn-in testing of electronic devices

The present invention relates to a burn-in station (BIS) for performing burn-in testing of electronic devices, comprising: a main frame; a plurality of burn-in drivers (BIDs) embedded the main frame and each including a plurality of slots; and a controller connected to each of the plurality of slots through a corresponding driver, and configured to generate command signals and analyze test results, wherein each of the plurality of slots is configured to receive a burn-in board (BIB), which is connectable to the driver provided in a same slot and configured to receive a device for testing, wherein the BIB is received in a slot case and is separated from the driver by the slot case.

[FIG. 5]